

# Metal- Oxide- Silicon (MOS) devices

- Principle of MOS Field Effect Transistor transistor operation

Metal (poly) gate on oxide between source and drain

Source and drain implants of opposite type to substrate.

Gate is biased to **invert** channel below oxide

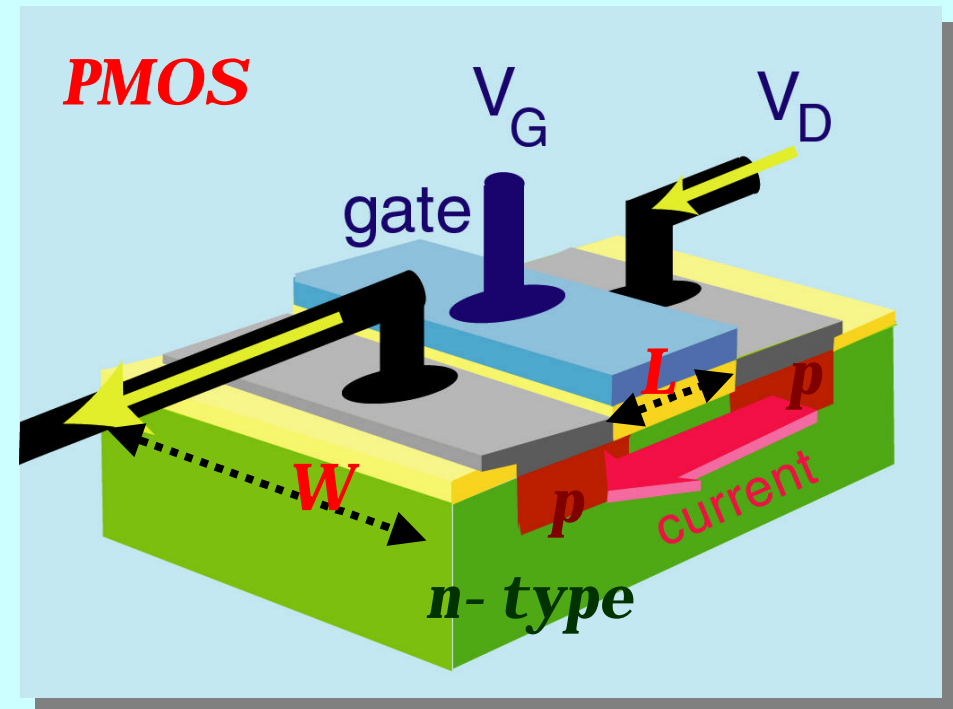
apply voltage bias to gate, which...

gives field across oxide

modulates current in conducting channel

transistor can be used as

*switch (digital) or amplifier (analogue )*



# MOS Field Effect Transistor

- **Operation - input signal is voltage on gate**

very high input impedance  $> 10^{12}$

- **I-V behaviour nMOS**

$V_G > V_T$  to switch on, vary  $V_{DS}$

linear region

$$I_{DS} \sim (V_G - V_T)V_{DS}$$

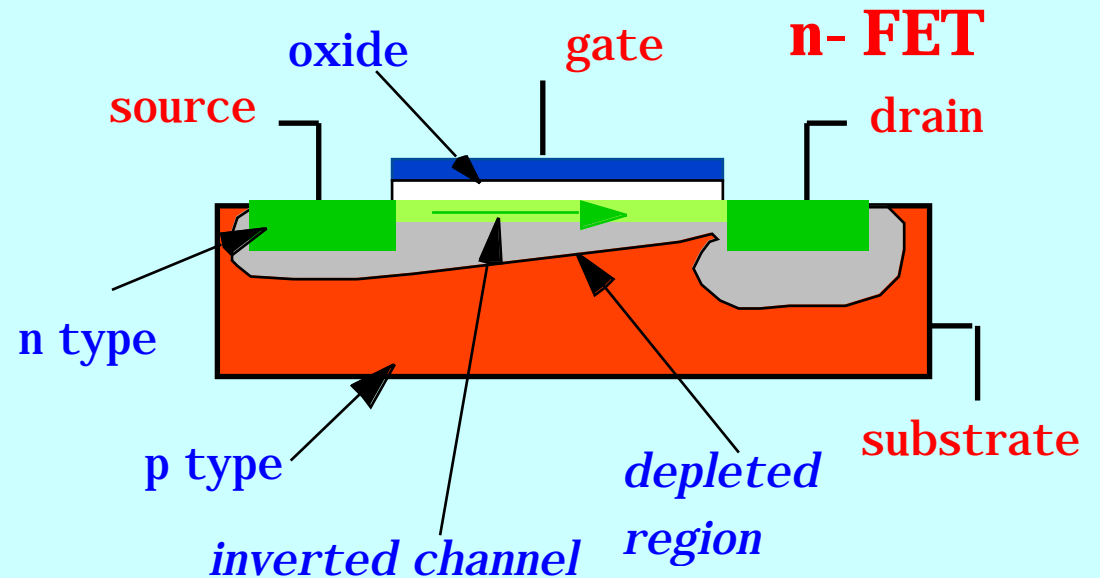
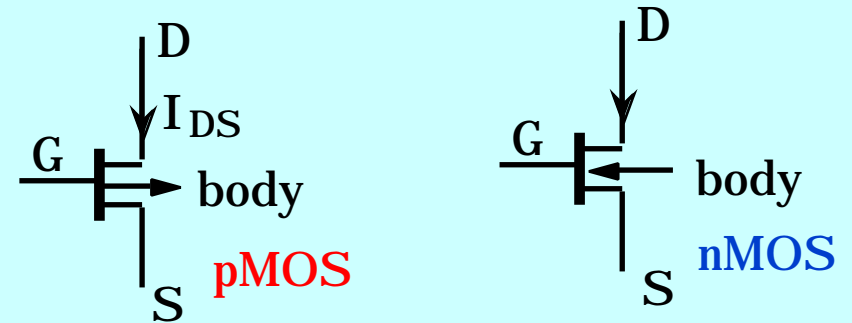
saturation region

channel “pinch off” near drain

$$I_{DS} \sim (V_G - V_T)^2$$

$$I_{DS} / V_{GS} = i_{ds} / v_{gs} = g_m = (2\mu C_{ox} I_{DS} W / L)^{1/2} \quad \text{transconductance}$$

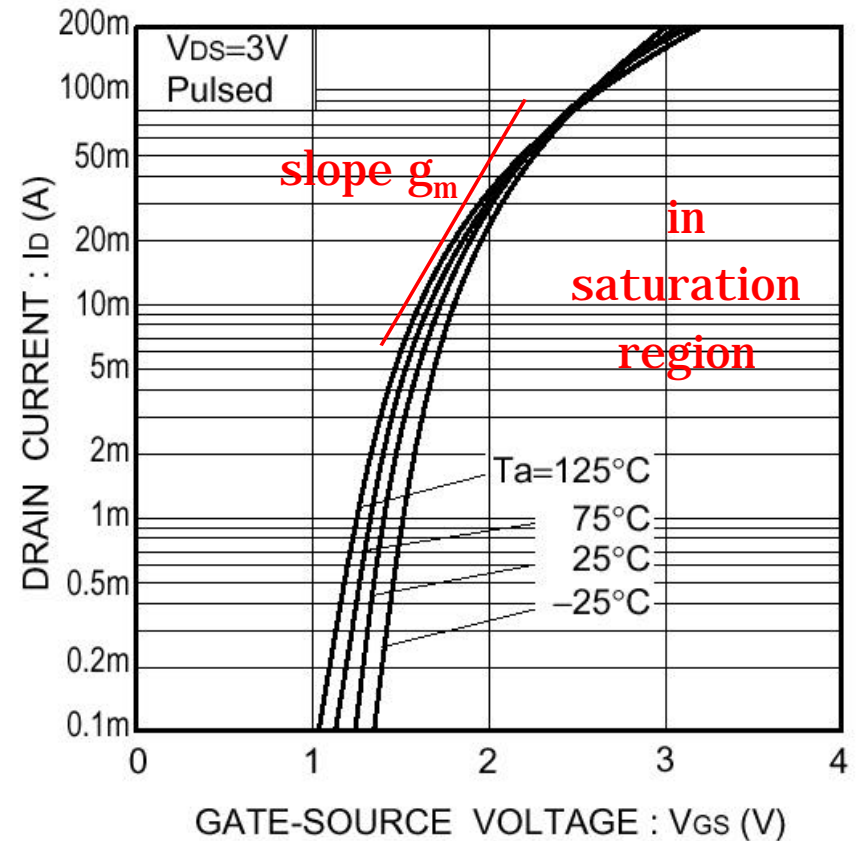
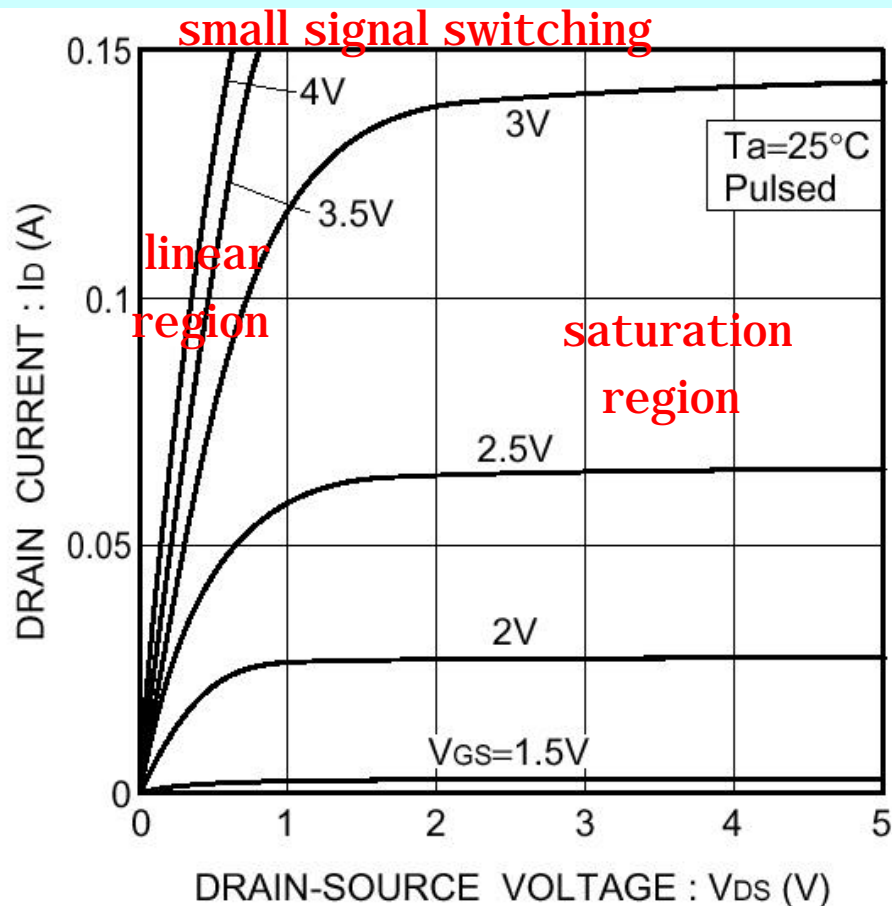
**defined by geometry & current only - important for IC design**



# Designing with MOSFETs

- Mostly operate in saturation - choice of gate-source voltage determines current but often bias with current source, so gate voltage "selected by" current

## 2SK3019



# Simple MOSFET applications

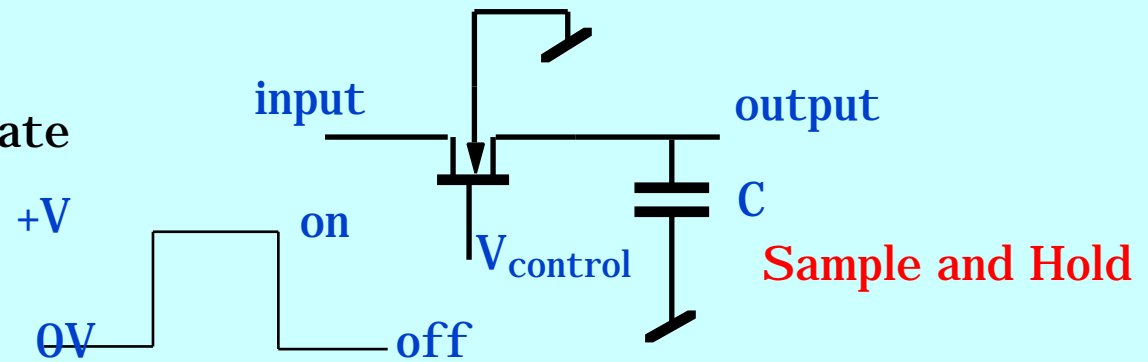
## • Voltage controlled switch

very high resistance in OFF state

$R_{ON} \sim 5 - 100$

fast response  $\sim$ nsec

bi-directional

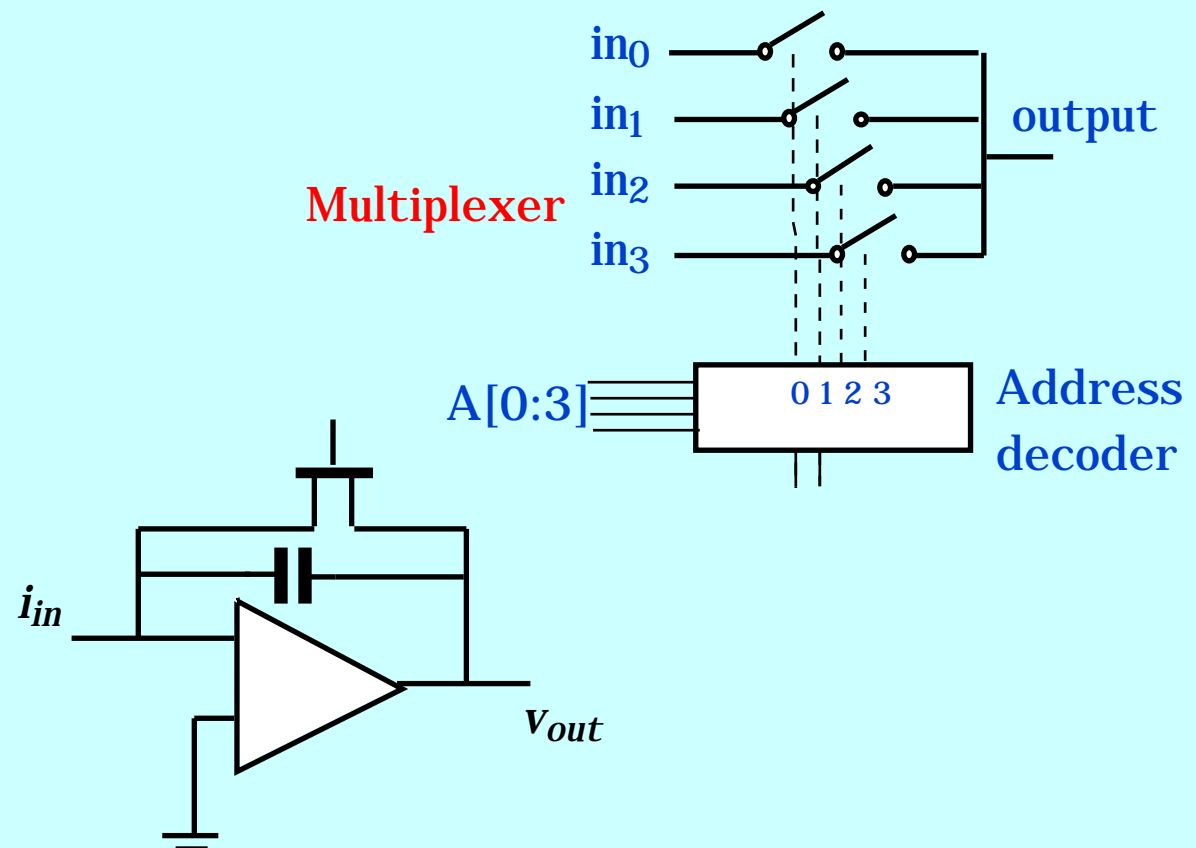


## • Voltage controlled resistor

operate in linear region

$R_{DS} \sim 1/(V_G - V_T)$

convenient for IC design



# ElectroStatic Discharge



- **MOS circuits are prone to damage from ESD**

gate oxides are thin layers - few nm in advanced technologies

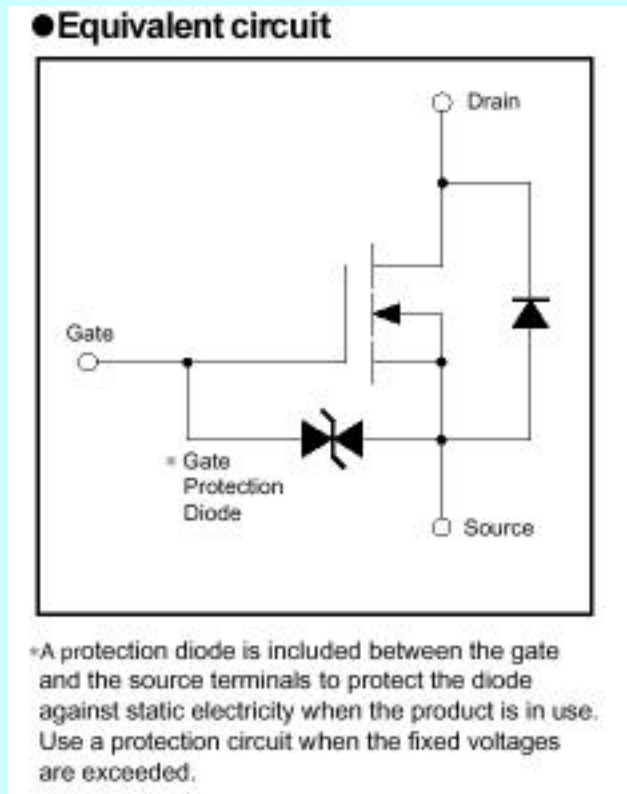
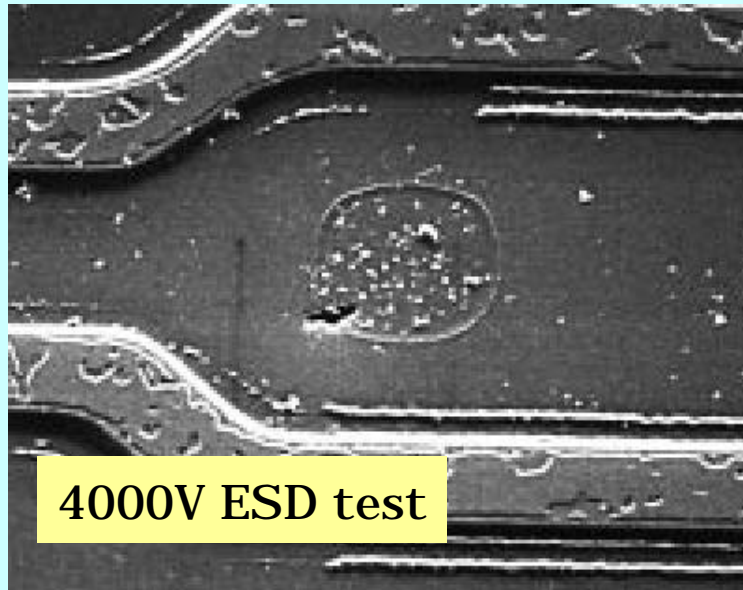
oxide breakdown field  $< 1000\text{MV/m} = 1\text{V/nm}$

- **Human body can easily charge to 30-40kV walking across carpet on a dry day**

precautions:

circuits designed with protection diodes

stand on conductive pad and earth body with wrist strap



# CMOS = Complementary MOS

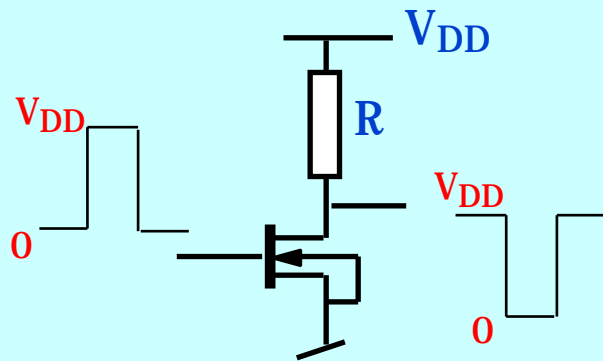
- Both pMOS and nMOS transistors on same wafer

by putting p-type "wells" into n-type wafer (or vice-versa)

build nMOS transistors in locally p-type region

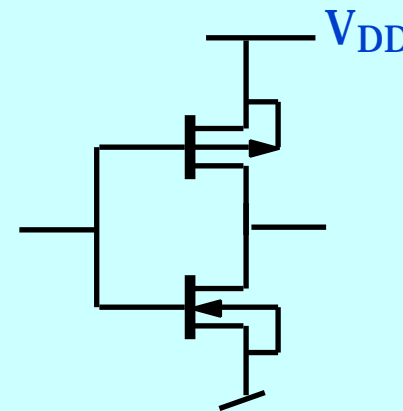
- Why?

NMOS inverter



NMOS consumes power in low state

CMOS inverter



CMOS version consumes power only when switching

basis of almost all modern logic

In IC technologies, accurate resistors are harder to make than C and transistors

# Junction FET

- **Almost identical to MOSFET - difference is**

Gate is implanted p-n junction

voltage on gate depletes bulk silicon

current conducting channel reduced or enlarged

$$\Delta V_{GS} \rightarrow \Delta I_{DS}$$

- **Characteristics - similar to MOSFET**

gate is reverse biased diode

high input impedance (  $10^9$  )

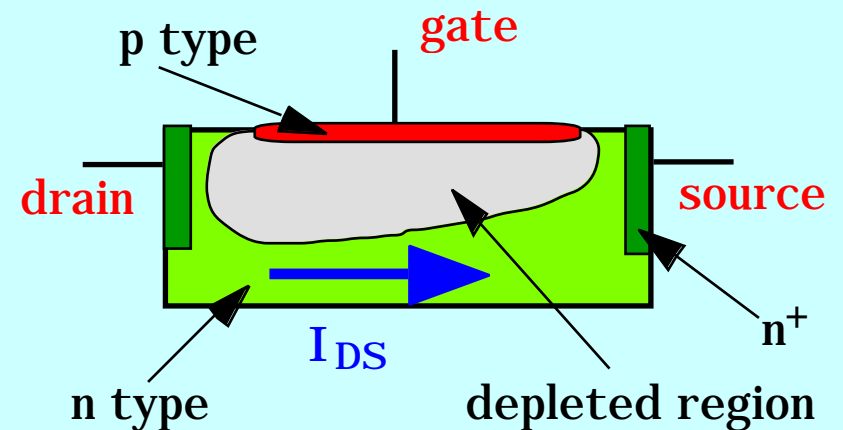
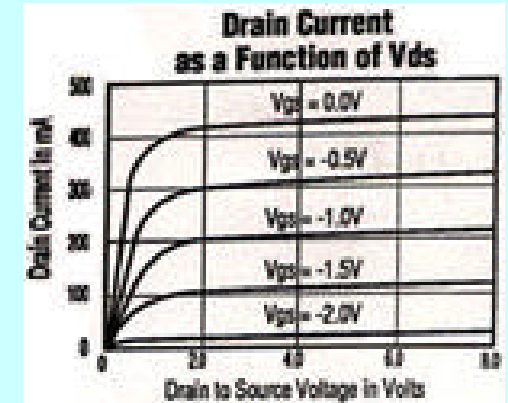
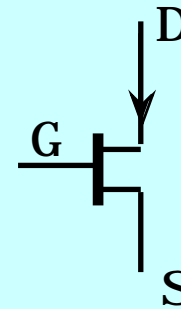
small current from diode leakage

usually operated in saturation

channel 'pinched off' by depletion.

“typical” values

$$g_m \sim 10\text{mA/V} = 1/100 = 10\text{mS}$$



# FET circuits

- Building blocks resemble bipolar circuits
- Source follower (cf emitter follower)

$$i_{ds} = g_m(v_g - v_s) = g_m(v_{in} - v_s)$$

$$v_{out} = v_s = i_{ds} R_S = g_m(v_{in} - v_s) R_S$$

$$v_{out}/v_{in} = g_m R_S / (1 + g_m R_S) \quad 1$$

$$R_{in} \sim 10^9 - 10^{12}$$

$$R_{out} = R_S || R_{DS} = R_S / (1 + g_m R_S)$$

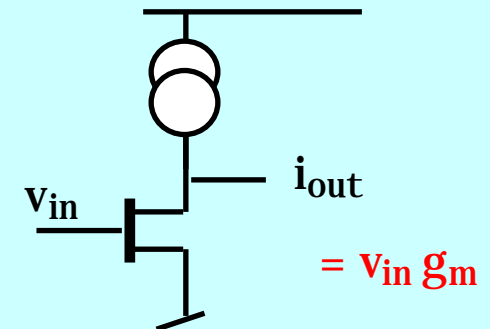
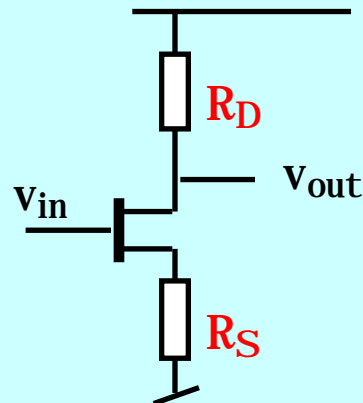
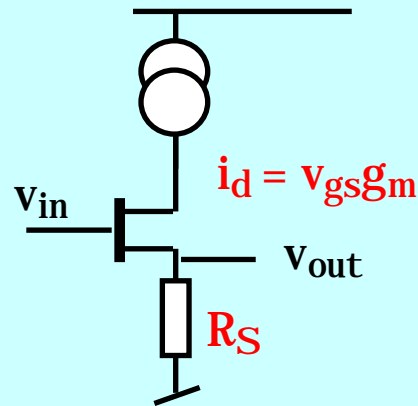
not low

- Common Source amplifier -

$$v_{out}/v_{in} = -g_m R_D / (1 + g_m R_S)$$

$R_{in}$  high

$$R_{out} = R_D || R_{DS} = R_D / (1 + g_m R_D)$$



but more common configuration uses current source with suitable load  $i_{out} = g_m v_{in}$



# FET limitations

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- **On Resistance**

although small, it contributes to RC time in fast switches

- **Capacitance**

inevitable capacitances between nodes, important for high speed circuits

$$C_{\text{gate}} \sim C_{\text{ox}}WL \text{ for MOSFETs}$$

- **Relevance to op-amps**

FET amplifiers have much higher input impedance

and draw much lower currents

- **Cautions**

- **Latch-up**

under certain conditions, parasitic bipolar transistors formed

MOS circuits can go into high current states - destructive

- **ESD**

care needed in handling

protection networks can degrade performance

# Another building block - the current mirror (if time)

- $Q_1$  &  $Q_2$  are identical transistors

$$V_{BE1} = V_{BE2} \text{ and } V_{BE} = (kT/q) \log_e I_E$$

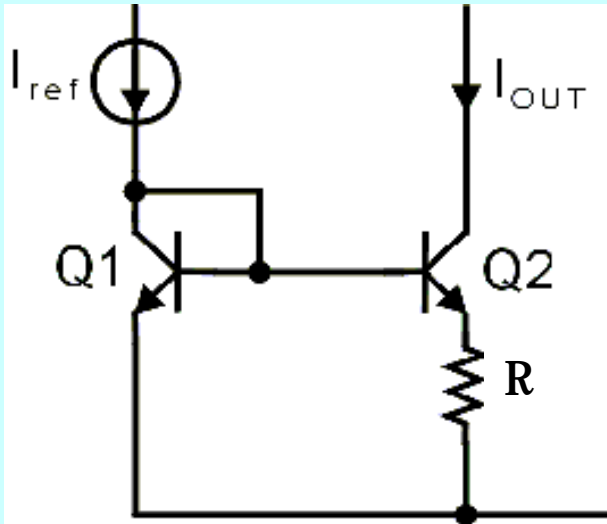
$$\text{so } I_{out} = I_{ref}$$

widely used in ICs where closely matched transistors are easy to construct - useful to program currents

- add a resistor

$$I_{out} = (kT/qR) \log_e (I_{ref}/I_{out})$$

$$\text{eg } R = 1k, I_{ref} = 1mA \Rightarrow I_{out} = 67\mu A$$

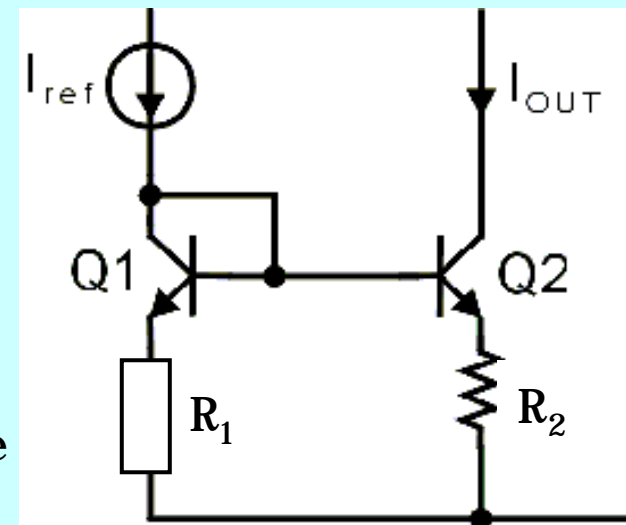
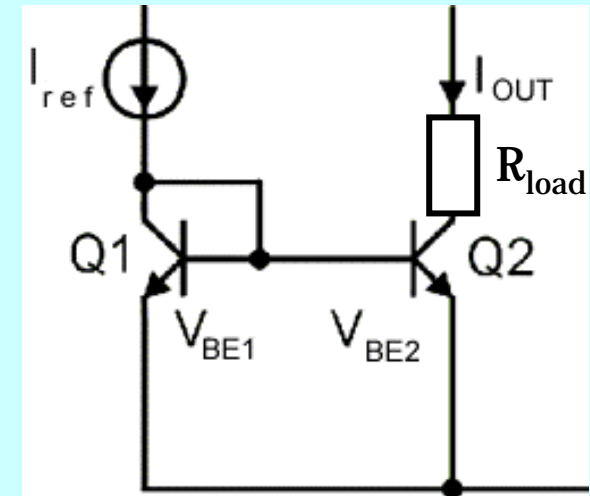


- add another resistor

$$V_{BE1} = V_{BE2}$$

$$I_1/I_2 = R_2/R_1$$

also works for discrete circuits



# Band-gap circuit

- To be more precise,

$V_{BE} \sim \log(\text{current density})$  so in non-matched transistors with same current, and ratio of emitter areas  $r$

$$V_{BE1} - V_{BE2} = (kT/q)\ln(r)$$

easy to achieve in IC technology

- Principle of AD590 T sensor

Proportional To Absolute Temperature (PTAT)

$$I_1 = I_2$$

$$V_{BE} = (kT/q)\ln(r) = I_1 R$$

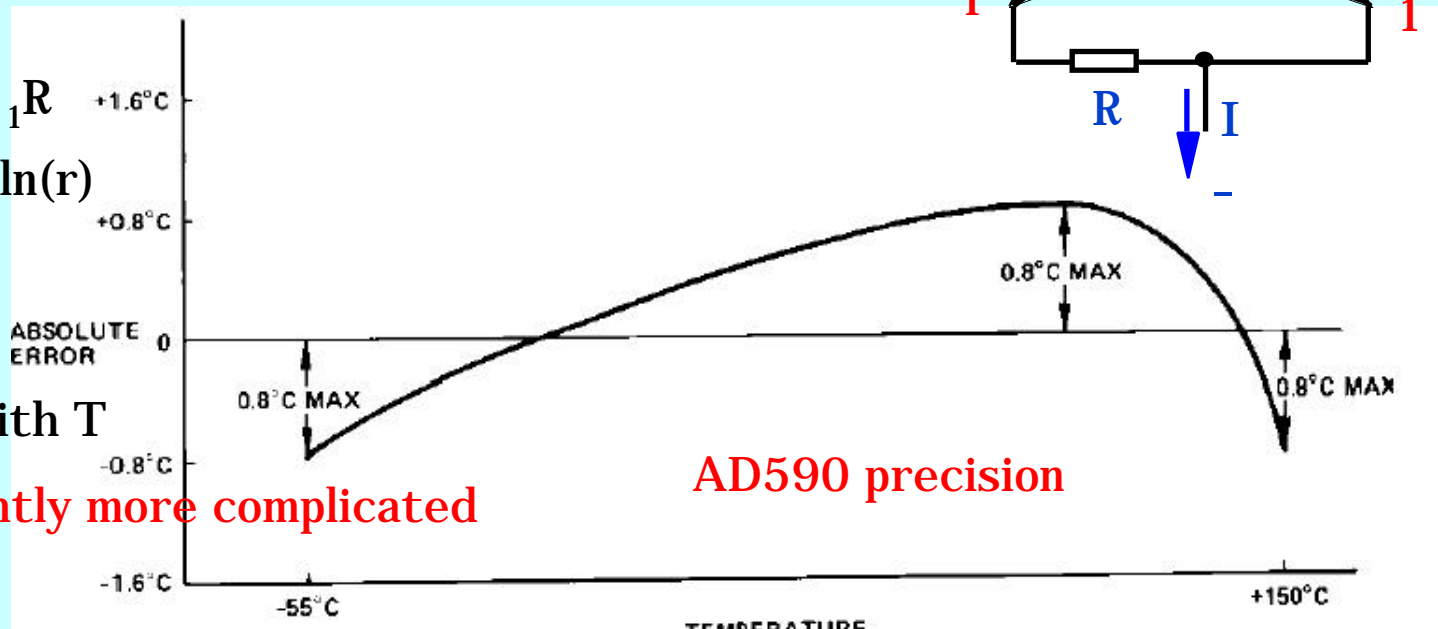
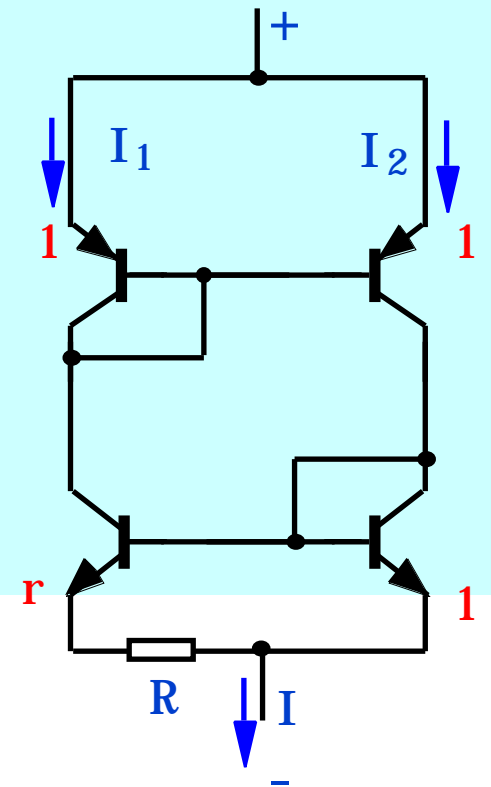
$$I = I_1 + I_2 = (2kT/qR)\ln(r)$$

$$r = 8 \quad R = 1k$$

$$I = 1\mu\text{A/K} @ 300\text{K}$$

$R$  should vary little with  $T$

- actual AD590 only slightly more complicated



AD590 precision

# Transistor differential amplifier

(for the ambitious)

- DC  $R_1$  is large, to act as current source

$$V_A = V_{EE} + I R_1$$

$$V_{E1} = V_A + I_1 R_E \quad V_{E2} = V_A + I_2 R_E \quad (\text{ignoring } r_e)$$

- AC

$$v_1 = v_A + i_1 R_E = i R_1 + i_1 R_E$$

$$v_2 = v_A + i_2 R_E = i R_1 + i_2 R_E$$

$$i = i_1 + i_2$$

$$v_1 - v_2 = (i_1 - i_2) R_E$$

$$v_0 = -i_2 R_C$$

- For differential inputs  $v_1 = -v_2$  so  $i = 0$

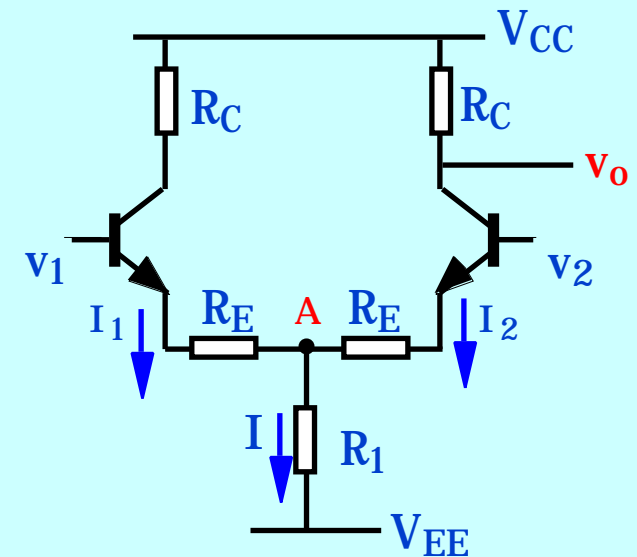
$$G_{\text{diff}} = v_0 / (v_2 - v_1) = R_C / 2R_E$$

- Common mode  $v_1 = v_2 = v_{\text{cm}}/2$

$$v_1 + v_2 = 2i R_1 + (i_1 + i_2) R_E = i(2R_1 + R_E)$$

$$G_{\text{cm}} = v_0 / v_{\text{cm}} = -R_C / (2R_1 + R_E)$$

$$\text{CMRR} = 2R_1 / R_E \quad R_1 \gg R_E$$

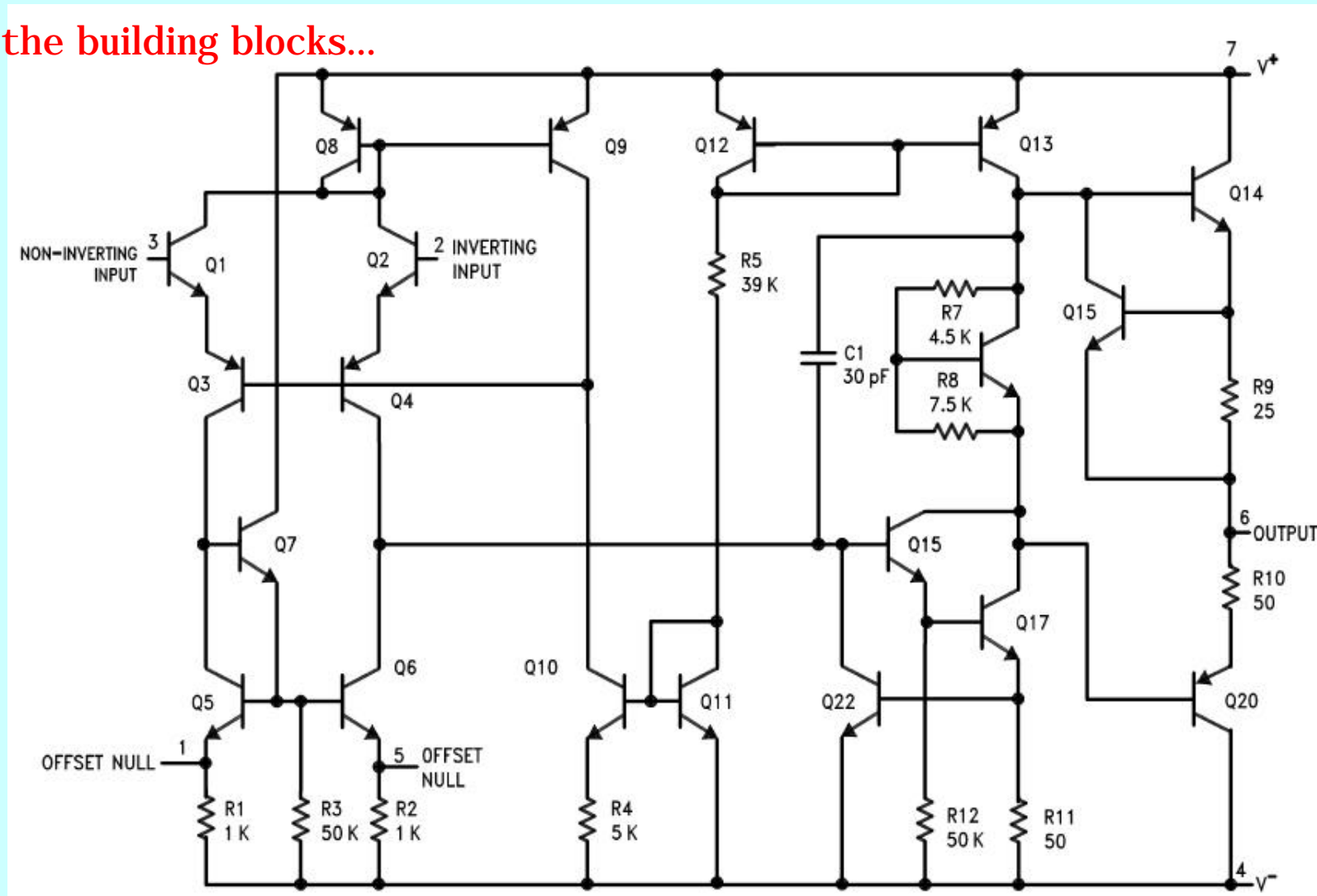


## Variants

- $R_C$  in Q1 loop omitted
- replace R by current source
- omit  $R_E$ s
- differential outputs

# What's inside an op-amp...

- Look for the building blocks...



MOS IC amplifiers look similar but currents determined by transistor aspect ratios